

2N5518

**DIFFERENTIAL PAIRS N-CHANNEL SILICON
 JUNCTION FIELD-EFFECT TRANSISTORS**

ABSOLUTE MAXIMUM RATINGS (25°C unless otherwise noted)

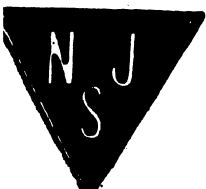
Gate-Drain or Gate-Source Voltage	-40 V
Gate Current	50 mA
Device Dissipation (each side), $T_A = 85^\circ\text{C}$, (derate 2.0 mW/°C)	250 mW
Total Device Dissipation, $T_A = 85^\circ\text{C}$, (derate 3.0 mW/°C)	375 mW
Storage Temperature Range	-65 to +150°C

ELECTRICAL CHARACTERISTICS (25°C unless otherwise noted)

Characteristic		Test Conditions	Min	Max	Unit	
I_{GSS}	Gate Reverse Current	$V_{GS} = -30\text{ V}, V_{DS} = 0$	25°C	-250	pA	
			150°C	-250	nA	
BV_{GSS}	Gate-Source Breakdown Voltage	$I_G = -1\ \mu\text{A}, V_{DS} = 0$	-40		V	
V_P	Gate-Source Pinch-Off Voltage	$V_{DS} = 20\text{ V}, I_D = 1\ \text{nA}$	-0.7	-4	V	
I_{DSS}	Drain Current at Zero Gate Voltage †	$V_{DS} = 20\text{ V}, V_{GS} = 0$	0.5	7.5	mA	
g_{fs}	Common-Source Forward Transconductance †		f = 1 kHz	1000	4000	μmho
g_{oss}	Common-Source Output Conductance				10	μmho
C_{rss}	Common-Source Reverse Transfer Capacitance		f = 1 MHz		5	pF
C_{iss}	Common-Source Input Capacitance				25	pF
\bar{e}_n	Equivalent Input Noise Voltage		f = 10 Hz		30	$\frac{\text{nV}}{\sqrt{\text{Hz}}}$
I_G	Gate Current	$V_{DG} = 20\text{ V}, I_D = 200\ \mu\text{A}$	25°C	-100	pA	
			125°C	-100	nA	
V_{GS}	Gate Source Voltage		-0.2	-3.8	V	
g_{fs}	Common-Source Forward Transconductance †		f = 1 kHz	500	1000	μmho
g_{oss}	Common-Source Output Conductance				1	μmho

*JEDEC Registered Data

† Pulse test required, pulsewidth 300 μs , duty cycle $\leq 3\%$



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*MATCHING CHARACTERISTICS

Characteristic	Test Conditions			Unit
		Min	Max	
$\frac{I_{DSS1}}{I_{DSS2}}$ Drain Current Ratio at Zero Gate Voltage †	$V_{DS} = 20 \text{ V}, V_{GS} = 0$	0.95	1	--
$ I_{G1} - I_{G2} $ Differential Gate Current	125°C		10	nA
$\frac{g_{fs1}}{g_{fs2}}$ Transconductance Ratio †	$V_{DG} = 20 \text{ V},$ $f = 1 \text{ kHz}$	0.95	1	--
$ g_{oss1} - g_{oss2} $ Differential Output Conductance	$f = 1 \text{ kHz}$ $I_D = 200 \mu\text{A}$		0.1	μmho
$ V_{GS1} - V_{GS2} $ Differential Gate-Source Voltage	$I_D = 200 \mu\text{A}$		15	mV
$\frac{\Delta V_{GS1} - V_{GS2} }{\Delta T}$ Gate-Source Voltage Differential Drift †	$T_A = 25^\circ \text{C}$ $T_B = 125^\circ \text{C}$		40	$\mu\text{V}/^\circ\text{C}$
		$T_A = -55^\circ \text{C}$ $T_B = 25^\circ \text{C}$	40	$\mu\text{V}/^\circ\text{C}$
CMRR	$V_{DD} = 10 \text{ to } 20 \text{ V},$ $I_D = 200 \mu\text{A}$			dB

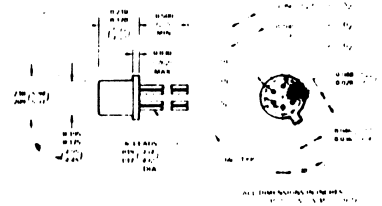
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† Pulse test required, pulsewidth 300 μs , duty cycle = 3%

‡ Measured at end points, T_A and T_B .

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**CMRR = $20 \log_{10} \Delta V_{DD} / \Delta |V_{GS1} - V_{GS2}|$ ($\Delta V_{DD} = 10\text{V}$)



All leads isolated from case